James M. Pitarresi, Ph.D.

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RESEARCH INTERESTS

Electronics Packaging Reliability, Computational Mechanics, Vibration Analysis/Testing

ACADEMIC EXPERIENCE

2013-present	Assistant Provost and Executive Director, Center for Learning and Teaching
2011-2013	SUNY Distinguished Teaching Professor and Chairman
2002-2011	Professor and Chairman
1994-2001	Associate Professor
1988-1993	Assisatnt Professor

Department of Mechanical Engineering Thomas J. Watson School of Engineering and Applied Science State University of New York at Binghamton

Major Thesis/Dissertation Advistment/

New York at Buffalo

EDUCATION

- Ph.D.-Structural Mechnics (Civil Engineering), September 198@at©tUniversity of New York at Buffalo Dissertation: Temporal Finite Elements in Structural Mechanics
- M.S.- Structural Mechanic (Civil Engineering), May 1983, Statteniversity of New York at Buffalo Thesis: Computer Modeling of a Twisted Composite Girder

H. Ouakad, F. A. S., M. I. Younis, T. Levo, dat. Pitarresi, "Response of an Electrostatically Actuated Microbeam to Drop-Table Test," IEEE fermal, Mechanical & Multiphysics Simulation and Experiments in Micro/Nano-Electronized Microsystems Conference, Eurosim 2010, Bordeaux, France, April, 26-, 2010

Younis, M. I, Miles, R., and Pitarresi, J., "TEffect of PCB Motion an Electrostatic Forces on the Response of MEMS Devices under Shock," Proceeding of the 2009 NSF CMMI Engineering Research and Innovation Conference, Honolulu, Hawaii, June, 2009.

Al-Yafawi, A., Yu, D., Park, SBP, itarresi, J., Chung, S., "Rebidity Assessment of Electronic Components under Random Vibration Loading," ECTC Conference, San Diego, CA May 27, 2009.

Argawal, A., Levo, T., Pitarresi, J., Roggeman, "Board Level Energy Comparison and Interconnect Reliability Modeling under Drop Test," ECTC Confect, San Diego, CA May 27, 2009, pp. 1694-1702.

Guruprasad, P., and Pitarresi, J., "Comparison of Joint Level Impact Fatigue Resistance and Board Level Drop Test," ECTC Conference, San Diego, CA, May 27, 2009, pp. 1708-1713.

S. B. Park, Chirag Shah, Jae B. Kwak, Changs

Pitarresi, J.M., Chaparlla, S, Sammakia, B., Ngulyen, atwardhan, V., Zhang, and Kelkar, N., "A Parametric Predictive Solder Joint Reliability Model for Wafer Level-Chip Scale Package," ECTC San Diego, CA, May 2002.

Pitarresi, J.M., Geng, P, Beltman, W., and Ling," Dynamic Modeling and Measurement of Personal

Holub, I.R, Pitarresi, J.M., and Singler, T.J., "EffecSodder Joint Geometry on the Predicted Fatigue Life of BGA Joints,"1996 InterSociety Conference on Thermal Phenomena (ITHER 1996) do, FL, May 29-June 1, 1996, pp.187-194.

Singler, T.J., Pitarresi, J.M., Holub, I.R., and Yin, Howard an Optimization Algorithm for Solder Joint Reliability," ASME 2nd International Electrom Packaging Conference, Vol. 20, 1155-1166, 1995.

Iannuzzelli, R., Pitarresi, J.M., and Rash, V., "Application of the Integrated Matrix Creep Method to Solder Joint Reliability Prediction, 1995 ASME Annual Meeting, Atlanta, GA, Nov. 1995

Pitarresi, J.M. and Akanda, A., "Random Vibration Response of a Surface Mounted Lead/Solder Joint," ASME International Electronic Backaging Conference, Vol Binghamton, NY, Sept. 1993, pp. 207-217. Macek, T. and Pitarresi, J.M., "Optimizanti of an Electrica Spring Connector, Proc. 43rd Electronic Components and Technology Conference FL, June 1-4, 1993, pp. 1083-1090.

Pitarresi, J.M. and Di Edwardo, A. V., "A Design Approach for the Systematic Improvement of Support Locations for Vibrating Circuit Cards, SME Journal of Electronics Packaging of 115, March 1993, pp.118-123.

Pitarresi, J.M. and Primavera, A., "Comparison of Vibration Modeling Techniques for Printed Circuit Cards," ASME Journal of Electronics Packagingol. 114, December 1992, pp. 378-383.

Prakash, V., Engel, P.A., Pitarresi, J.M., Albert, T. and Westby, G., "Stress Analysis of Component Attachments to Printed Circuit Board Söldering and Surface Mount Technol (1993).

Pitarresi, J.M. and Kunz, R., "A Rapid Techniquet**for** Estimation of the Optimal Support Locations of Vibrating Plates," ASME Journal of Vibration and Acoustics 114, No. 1, January 1992, pp. 112-118.

Pitarresi, J.M., Celetka, D., Coldwel, R. and Smith, "Dhe Smeared Properties Approach to FE Vibration Modeling of Printed Circuit Cards, ASME Journal of Electronics Packagingol. 113, September 1991, pp. 250-257.

Pitarresi, J.M. and Manolis, G.D., "The Temporalife Element Method for Structural Dynamics," International Journal of Computers and Structures. 41, No. 3, 1991, pp. 647-656.

Pitarresi, J.M. and Di Edwardo, A., "Optimal sport Locations for Circuit Cards Populated with Modules," ASME Winter Conference tlanta, Ga., December 1-6, paper no. 91-WA-EEP-2, 1991.

Pitarresi, J.M. and Primavera, A., "Comparison of Vibration Modeling Techniques for Printed Circuit Cards," ASME Winter Conference Ilanta, Ga., December 1-6 aper no. 91-WA-EEP-34, 1991.

Pitarresi, J.M., "Modeling of Printed Cirit Cards Subject to Vibration", IEE Proceedings of the Circuits and Systems Conference Were Worleans, LA, May 3-5, 1990, pp. 2104-2107.

Prakash, V., Engel, P.A., Pitarresi, J.M., Albert, T. and Westby, G., "Stress Analysis of Component Attachments to Printed Circuit Boards," Proc. Int'l Electronic Packaging Soc. Conf., San Diego, CA, Vol 2, pp. 794-804, Sept, 1991.

Vehemeir, M. and Pitarresi, J.M., "Control and Structural Synthesis - a New Approdetthe and Ce(J8(r)5.T97 TD 0 Tc]TJ /T5868 1-6(199)R)4. s00051(.)-. [(McS43.8(le)6.r)-1.1(d)4.2(5(T4 1 Tf 16.2335 8.(Ma90

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Cha, J.Z., Pitarresi, J.M. and Soong, T.T.ptional Design Procedures for Active Structures SCE J. of Structural EngineeringVol. 114, No. 2, Dec. 1988, pp. 2710-2723.

Pitarresi, J.M. and Soong, T.T., "Optimal Design of Active Structures," Computer Applications in <u>Structural Engineering</u>, D. R. Jenkins, Ed., 1987 pp. 591-597.

Gellin, S. and Pitarresi, J.M., "Temporal Finite Elements for Nonlinear Truss Analysis," IV International Symposium on Numerical Methods in Engineering Aţlantergia, pp. 547-552, March 1986.

BOOKS AND CHAPTERS

Shames, I.H., and Pitarresi, J.M., Introduction to Solid Mechanford Prentice-Hall, 2000.

Pitarresi, J.M.Modeling of Circuit Cards Subject to Vibration to Vibration Packaging, Vol. 2, J. E. Morris, Ed., Van stime Reinhold, New York, 1991, pp. 103-137.

EXTERNALLY-SPONSORED RESEARCH

Vibration Reliability Measurement and Modeling, UniscelrInstruments Corp., 9/2012 – 8/2013, \$153,000 (Co-PI)

Research on electronics Reliability, Universal Instents Corp., 1/9/2012 - 5/18/12, \$182,740 (Co-PI)

Engineering 2020 eSTEM Program, NSF, 5/10 – 5/15, \$600,000 (Co-PI).

Microbeams under Mechanical Shock and Electros **fattuation** Accounting for the Effects of Circuit Board and Package Motion, NSF, 9/07-8/10, \$318,992 (Co-PI).

MEMS micro-switch shock reliability, Office of Nal/Research, Surface WarferDivision, 5/1/05 – 12/31/06, \$158,150 (Co-PI).

Die Stress measurement and modeling, Analog Devices, Inc., 2/05 – 1/06, \$48,481 (Co-PI).

Nano-mechanical prognostics of microelectronic structures, US Army–CERDEC, 11/03 – 10/04, \$9,500. (PI)

Reliability Assessment of Wafer Level Chip-Scallackages, National Semiconductor Corporation, 1/1/2001 – 12/31/2001, \$59,871 (PI)

Vibration Analysis of Personal Computer Systems, Intel Corporation, 1/00 – 12/02, \$168,252 (PI)

Constitutive Modeling and Characterization of Larade Solder Alloys, Semiconductor Research Corporation, 9/01 – 8/03, \$210,000 (Co-PI)

Assembly and Operational Assessment of Tiled Shipp Flat Panel Displays, 11/00 – 10/02, Rainbow Displays Corporation/NIST, \$145,951 (Co-PI)

Stress Discontinuity Modeling for Flat Panel Displays, NSF, 1/1/99-12/31/01, \$200,000, (Co-PI).

Modeling and Measurement of Di

Mechanical Performance of a Motion Simulator Platform, Doron Corp. 1/20/00-12/31/00, \$42,100 (PI).

Electronic Packaging: Characterization and Modeling, Universal Inst. Corp., 1/00-12/00, \$168,989. (PI)

Modeling and Measurement of Warpage in Electronic Packages, NSF/NYS/IEEC, 6/99-5/01, \$108,629.

Resistance Spectroscopy Applied to Solder Joint Fatigue Measurement, NSF/NYS/IEEC, 6/99-5/01, \$112,445. (PI)

Reliability Modeling of Chip-Scale Packaging Assemblie Instruments Crop., 5/1/97-12/31/99, \$252,869, (PI).

Development of a Micro-Mechanical Solder Constitute Law, NSF/NYS/IEEC9/97-6/98 \$22,690. (PI)

Moiré Measurement and Vibration Modeling of Electronic Packages, NASA/JPL, \$2,500, 6/97-7/97. (PI)

Verification of Computational Modeling Techniques Using Experimental Modal Analysis, IBM Corporation, 6/89-3/90, \$24,998. (PI)